Se	arcn	Note	S

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/030,464	FEUSSNER ET AL.	
Examiner	Art Unit	
Yong D. Pak	1652	

SEARCHED				
Class	Subclass	Date	Examiner	
435	189	4/28/2005	YP	
435	252.3	4/28/2005	YP	
435	320.1	4/28/2005	YP	
435	69.1	4/28/2005	YP	
435	71.1	4/28/2005	YP	
435	440	4/28/2005	YP	
435	4	4/28/2005	YP	
435	25	4/28/2005	YP	
536	23.2	4/28/2005	ΥP	
536	23.7	4/28/2005	YP	
·		-		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	<u> </u>			

SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
stic: S73865 of EMBL database	4/28/2005	YP
stn/east: see search history	4/28/2005	ΥP
Inventor search	4/28/2005	ΥP
		·